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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 17473.2-2008

**Test methods of precious metals pastes used for
microelectronics -- Determination of fineness**

(English Translation)

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Foreword

This standard is an integrated revision of GB/T 17473-1998 " Test methods of precious metal pastes used for thick film microelectronics" (all parts). It is divided into 7 parts:

- GB/T 17473.1-2008 Test methods of precious metals pastes used for microelectronics - Determination of solids content;
- GB/T 17473.2-2008 Test methods of precious metals pastes used for microelectronics - Determination of fineness;
- GB/T 17473.3-2008 Test methods of precious metals pastes used for microelectronics - Determination of sheet resistance;
- GB/T 17473.4-2008 Test methods of precious metals pastes used for microelectronics - Determination of adhesion;
- GB/T 17473.5-2008 Test methods of pastes used for microelectronics - Determination of viscosity;
- GB/T 17473.6-2008 Test methods of precious metal pastes used for microelectronics - Determination of resolution;
- GB/T 17473.7-2008 Test methods of precious metals pastes used for

microelectronics - Determination of solderability and solderleaching resistance.

This Part is Part 2 of GB/T 17473-2008.

This part replaces GB/T 17473.2-1998 "Test methods of precious metal pastes used for thick film microelectronics - Determination of fineness".

Compared with GB/T 17473.2-1998, this Part mainly has the following changes:

- CHANGE the original standard name into "Test methods of precious metals pastes used for microelectronics - Determination of fineness";
- In the Scope, DELETE the content that "non-precious metal pastes can also be implemented with reference to this standard";
- CANCEL the requirements for testing specimen that "not less than 5 sets,

2 g per set"; it only requires that the specimen is thoroughly mixed well.

This Part was proposed by China Nonferrous Metals Industry Association.

This Part shall be under the jurisdiction of the National Non-ferrous Metals

Test methods of precious metals pastes used for
microelectronics - Determination of fineness

1 Scope

This Part specifies the scraper determination method for the fineness of precious metal pastes, which are used in microelectronics technology.

This Part applies to the determination of the fineness of precious metal pastes, for microelectronics technologies.

2 Normative references

The provisions in following documents become the provisions of this Part through reference in this Part. For the dated references, the subsequent amendments (excluding corrections) or revisions do not apply to this Part; however, parties who reach an agreement based on this Part are encouraged

to study if the latest versions of these documents are applicable. For undated references, the latest edition of the referenced document applies.

GB/T 8170 Rules of rounding off for numerical values & expression and judgement of limiting values

3 Method principle

The paste is placed on the fineness meter, scraped from top to bottom by a scraper. The size of the particles is determined visually, according to the position of the longitudinal stripes in the groove.

4.1 Scraper fineness meter: The measuring range is 0 μm ~ 25 μm ; the accuracy is 1 μm ; the calibration period is half a year.

4.2 Sizing knife: A stainless steel knife, which has a wooden handle AND a thickness of 1 mm.

4.3 Scraper.

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